

## Product Advisory (PA)

**Subject:** Correction to the Renesas HSO-26C31, HSO-26C32, HSO-26CLV31, HSO-26CLV32, HSO-26CT31, HSO-26CT32 Datasheets and SMDs

**Publication Date:** 10/22/2021

**Effective Date:** 10/22/2021

### Revision Description:

Initial Release

### Description of Change:

This notice is to inform you of Datasheet/SMD corrections as below;

1. Updates to Die Characteristics section. Die Thickness Dimension is updated on datasheet and SMD. Glassivation, M1 Thickness, M2 Thickness is only updated on datasheet, no change to SMD.

Corrections are reflected in Appendix A of the notice.

### Products Impacted by the change;

SMD #	Renesas Part#	SMD #	Renesas Part#	SMD #	Renesas Part#
5962F9568901V9A	HSO-26C32RH-Q	5962F9568902V9A	HSO-26CLV32RH-Q	5962F9563201V9A	HSO-26CT31RH-Q
N/A	HSO-26C32RH/SAMPLE	N/A	HSO-26CLV32RH/SAMPLE	N/A	HSO-26C31RH/SAMPLE
5962F9568903V9A	HSO-26C32EH-Q	5962F9568904V9A	HSO-26CLV32EH-Q	5962F9666301V9A	HSO-26C31RH-Q
5962F9666302V9A	HSO-26CLV31RH-Q	5962F9563101V9A	HSO-26CT32RH-Q	5962F9666303V9A	HSO-26C31EH-Q
5962F9666304V9A	HSO-26CLV31EH-Q	N/A	HSO-26CT32RH/SAMPLE		
N/A	HSO-26CLV31RH/SAMPLE	5962F9563102V9A	HSO-26CT32EH-Q		

### Reason for Change:

Change corrects the datasheet and SMD to reflect the actual product characteristics. Details regarding the change are contained within Appendix A, for an updated datasheet please contact your local sales or marketing representative.

### Impact on fit, form, function, quality & reliability:

The change will have no impact on the form, fit, function, quality, reliability and environmental compliance of the devices.

### Product Identification:

There have been no changes to the product, this is a documentation correction only. There will be no change in the external marking of the products.

**Qualification status:** Not Applicable, correction only

**Sample availability:** 10/22/2021

**Device material declaration:** Available upon request

*Questions or requests pertaining to this change notice, including additional data or samples, must be sent to Intersil within 30 days of the publication date.*

For additional information regarding this notice, please contact your regional change coordinator (below)			
Americas: <a href="mailto:PCN-US@Renesas.COM">PCN-US@Renesas.COM</a>	Europe: <a href="mailto:PCN-EU@Renesas.COM">PCN-EU@Renesas.COM</a>	Japan: <a href="mailto:PCN-JP@Renesas.COM">PCN-JP@Renesas.COM</a>	Asia Pac: <a href="mailto:PCN-APAC@Renesas.COM">PCN-APAC@Renesas.COM</a>

## Appendix A: Datasheet changes for HS0-26C32

### FROM:

HS-26C32RH, HS-26C32EH

#### Die Characteristics

##### DIE DIMENSIONS:

78 mils x 123 mils  
(1970µm x 3120µm)

##### INTERFACE MATERIALS:

##### Glassivation:

Type: SiO<sub>2</sub>  
Thickness: 10kÅ ± 1kÅ

##### Top Metallization:

M1: Mo/TiW  
Thickness: 5800Å  
M2: Al/Si/Cu  
Thickness: 5800Å

##### Worst Case Current Density:

<2.0 x 10<sup>-5</sup> A/cm<sup>2</sup>

##### Bond Pad Size:

110µm x 100µm

### TO:

HS-26C32RH, HS-26C32EH

#### Die Characteristics

##### DIE DIMENSIONS:

78 mils x 123 mils x 19 mils ±1 mil  
(1981µm x 3124µm x 483µm ±25µm)

##### INTERFACE MATERIALS:

##### Glassivation:

Type: PSG (Phosphorus Silicon Glass)  
Thickness: 8kÅ ±1kÅ

##### Metallization:

M1: Mo/TiW (Bottom)  
Thickness: 5800Å ±1kÅ  
M2: Al/Si/Cu (Top)  
Thickness: 10kÅ ±1kÅ

##### Substrate:

AVLSI1RA

##### Backside Finish:

Silicon

##### ASSEMBLY RELATED INFORMATION:

##### Substrate Potential (Powered Up):

Internally tied to V<sub>DD</sub>

##### Worst Case Current Density:

< 2.0e5 A/cm<sup>2</sup>

##### Bond Pad Size:

110µm x 100µm

##### Transistor Count:

315

## Datasheet changes for HS0-26C31

### FROM:

HS-26C31RH, HS-26C31EH

#### Die Characteristics

##### DIE DIMENSIONS:

96.5 mils x 195 mils x 21 mils  
(2450 x 4950)

##### INTERFACE MATERIALS:

##### Glassivation:

Type: PSG (Phosphorus Silicon Glass)  
Thickness: 10kÅ ±1kÅ

##### Metallization:

M1: Mo/TiW  
Thickness: 5800Å  
M2: Al/Si/Cu (Top)  
Thickness: 10kÅ ±1kÅ

##### Substrate:

AVLSI1RA

##### Backside Finish:

Silicon

##### ASSEMBLY RELATED INFORMATION:

##### Substrate Potential (Powered Up):

V<sub>DD</sub>

##### ADDITIONAL INFORMATION:

##### Worst Case Current Density:

<2.0x10<sup>5</sup> A/cm<sup>2</sup>

##### Bond Pad Size:

110µmx100µm

### TO:

HS-26C31RH, HS-26C31EH

#### Die Characteristics

##### DIE DIMENSIONS:

96.5 mils x 195 mils x 19 mils ±1mil  
(2451µm x 4953µm x 483µm ±25µm)

##### INTERFACE MATERIALS:

##### Glassivation:

Type: PSG (Phosphorus Silicon Glass)  
Thickness: 8kÅ ±1kÅ

##### Metallization:

M1: Mo/TiW (Bottom)  
Thickness: 5800Å ±1kÅ  
M2: Al/Si/Cu (Top)  
Thickness: 10kÅ ±1kÅ

##### Substrate:

AVLSI1RA

##### Backside Finish:

Silicon

##### ASSEMBLY RELATED INFORMATION:

##### Substrate Potential (Powered Up):

Internally tied to V<sub>DD</sub>

##### ADDITIONAL INFORMATION:

##### Worst Case Current Density:

<2.0x10<sup>5</sup> A/cm<sup>2</sup>

##### Bond Pad Size:

110µmx100µm

## Datasheet changes for HS0-26CLV31

### FROM:

HS-26CLV31RH, HS-26CLV31EH

#### Die Characteristics

##### DIE DIMENSIONS:

96.5 mils x 195 mils x 21 mils  
(2450 x 4950)

##### INTERFACE MATERIALS:

###### Glassivation:

Type: PSG (Phosphorus Silicon Glass)  
Thickness: 8kÅ ±1kÅ

###### Metallization:

Bottom: Mo/TiW  
Thickness: 5800Å ±1kÅ  
Top: AlSiCu (Top)  
Thickness: 10kÅ ±1kÅ

##### Substrate:

AVLSI1RA

##### Backside Finish:

Silicon

##### ASSEMBLY RELATED INFORMATION:

###### Substrate Potential (Powered Up):

V<sub>DD</sub>

###### ADDITIONAL INFORMATION:

###### Worst Case Current Density:

<2.0x10<sup>5</sup>A/cm<sup>2</sup>

###### Bond Pad Size:

110µm x 100µm

### TO:

HS-26CLV31RH, HS-26CLV31EH

#### Die Characteristics

##### DIE DIMENSIONS:

96.5 mils x 195 mils x 19 mils ±1mil  
2451µm x 4953µm x 483µm ±25µm

##### INTERFACE MATERIALS:

###### Glassivation:

Type: PSG (Phosphorus Silicon Glass)  
Thickness: 8kÅ ±1kÅ

###### Metallization:

M1: Mo/TiW (Bottom)  
Thickness: 5800Å ±1kÅ  
M2: AlSiCu (Top)  
Thickness: 10kÅ ±1kÅ

##### Substrate:

AVLSI1RA

##### Backside Finish:

Silicon

##### ASSEMBLY RELATED INFORMATION:

###### Substrate Potential (Powered Up):

Internally tied to V<sub>DD</sub>

###### ADDITIONAL INFORMATION:

###### Worst Case Current Density:

<2.0x10<sup>5</sup>A/cm<sup>2</sup>

###### Bond Pad Size:

110µm x 100µm

## Datasheet changes for HS0-26CLV32

### FROM:

HS-26CLV32RH, HS-26CLV32EH

#### Die Characteristics

##### DIE DIMENSIONS:

78 mils x 123 mils x 21 mils  
(1970µm x 3120µm)

##### INTERFACE MATERIALS:

###### Glassivation:

Type: PSG (Phosphorus Silicon Glass)  
Thickness: 8kÅ ±1kÅ

###### Substrate:

AVLSI1RA, Silicon backside, V<sub>DD</sub> backside potential

##### Metallization:

Bottom: Mo/TiW  
Thickness: 5800Å ±1kÅ  
Top: Al/Si/Cu  
Thickness: 10kÅ ±1kÅ

##### Worst Case Current Density:

<2.0 x 10<sup>5</sup>A/cm<sup>2</sup>

##### Bond Pad Size:

110µm x 100µm

### TO:

HS-26CLV32RH, HS-26CLV32EH

#### Die Characteristics

##### DIE DIMENSIONS:

78 mils x 123 mils x 19mils ±1mil  
(1981µm x 3124µm x 483µm ±25µm)

##### INTERFACE MATERIALS:

###### Glassivation:

Type: PSG (Phosphorus Silicon Glass)  
Thickness: 8kÅ ±1kÅ

###### Metallization:

M1: Mo/TiW (Bottom)  
Thickness: 5800Å ±1kÅ  
M2: Al/Si/Cu (Top)  
Thickness: 10kÅ ±1kÅ

##### Substrate:

AVLSI1RA

##### Backside Finish:

Silicon

##### ASSEMBLY RELATED INFORMATION:

###### Substrate Potential (Powered Up):

Internally tied to V<sub>DD</sub>

###### Worst Case Current Density:

< 2.0e5A/cm<sup>2</sup>

###### Bond Pad Size:

110µm x 100µm

###### Transistor Count:

315

## Datasheet changes for HS0-26CT32

### FROM:

HS-26CT32RH, HS-26CT32EH

#### Die Characteristics

##### DIE DIMENSIONS:

78 mils x 123 mils  
(1970µm x 3120µm)

##### INTERFACE MATERIALS:

##### Glassivation:

Type: PSG (Phosphorus Silicon Glass)  
Thickness: 10kÅ ±1kÅ

##### Top Metallization:

M1: Mo/TiW  
Thickness: 5800Å  
M2: Al/Si/Cu  
Thickness: 10kÅ ±1kÅ

##### Substrate:

AVLSI1RA

##### Backside Finish:

Silicon

##### ASSEMBLY RELATED INFORMATION:

##### Substrate Potential:

V<sub>DD</sub> (When Powered Up)

##### ADDITIONAL INFORMATION:

##### Worst Case Current Density:

<2.0 x 10<sup>5</sup> A/cm<sup>2</sup>

##### Transistor Count:

240

##### Bond Pad Size:

110µm x 100µm

### TO:

HS-26CT32RH, HS-26CT32EH

#### Die Characteristics

##### DIE DIMENSIONS:

78 mils x 123 mils x 19 mils ±1mil  
(1981µm x 3124µm x 483µm ±25µm)

##### INTERFACE MATERIALS:

##### Glassivation:

Type: PSG (Phosphorus Silicon Glass)  
Thickness: 8kÅ ±1kÅ

##### Metallization:

M1: Mo/TiW (Bottom)  
Thickness: 5800Å ±1kÅ  
M2: Al/Si/Cu (Top)  
Thickness: 10kÅ ±1kÅ

##### Substrate:

AVLSI1RA

##### Backside Finish:

Silicon

##### ASSEMBLY RELATED INFORMATION:

##### Substrate Potential (Powered Up):

Internally tied to V<sub>DD</sub>

##### Worst Case Current Density:

< 2.0e5 A/cm<sup>2</sup>

##### Bond Pad Size:

110µm x 100µm

##### Transistor Count:

315

## Datasheet changes for HS0-26CT31

### FROM:

HS-26CT31RH, HS-26CT31EH

#### Die Characteristics

##### DIE DIMENSIONS:

96.5 milx195 milsx21 mils  
(2450x4950)

##### INTERFACE MATERIALS:

##### Glassivation:

Type: PSG (Phosphorus Silicon Glass)  
Thickness: 10kÅ ± 1kÅ

##### Metallization:

M1: Mo/TiW  
Thickness: 5800Å  
M2: Al/Si/Cu (Top)  
Thickness: 10kÅ ±1kÅ

##### Substrate:

AVLSI1RA

##### Backside Finish:

Silicon

##### ASSEMBLY RELATED INFORMATION:

##### Substrate Potential (Powered Up):

V<sub>DD</sub>

##### ADDITIONAL INFORMATION:

##### Worst Case Current Density:

<2.0x10<sup>5</sup> A/cm<sup>2</sup>

##### Bond Pad Size:

110µmx100µm

### TO:

HS-26CT31RH, HS-26CT31EH

#### Die Characteristics

##### DIE DIMENSIONS:

96.5 mils x 195 mils x 19 mils ±1mil  
2451µm x 4953µm x 483µm ±25µm

##### INTERFACE MATERIALS:

##### Glassivation:

Type: PSG (Phosphorus Silicon Glass)  
Thickness: 8kÅ ±1kÅ

##### Metallization:

M1: Mo/TiW (Bottom)  
Thickness: 5800Å ±1kÅ  
M2: Al/Si/Cu (Top)  
Thickness: 10kÅ ±1kÅ

##### Substrate:

AVLSI1RA

##### Backside Finish:

Silicon

##### ASSEMBLY RELATED INFORMATION:

##### Substrate Potential (Powered Up):

Internally tied to V<sub>DD</sub>

##### ADDITIONAL INFORMATION:

##### Worst Case Current Density:

<2.0x10<sup>5</sup> A/cm<sup>2</sup>

##### Bond Pad Size:

110µmx100µm

## Summary

SMD #	Renesas Part#	Die Dimension		Glassivation type/thickness		M1 Thickness		M2 Thickness	
		OLD	NEW	OLD	NEW	OLD	NEW	OLD	NEW
5962F9568901V9A	HS0-26C32RH-Q	Datasheet=78 x 123 x <b>21</b> mils SMD=78 x 123 x <b>21</b> mils	78 x 123 x <b>19mils</b> +/-1mil	SIO2 10kA +/-1kA	PSG 8kA +/-1kA	5800A	5800A +/-1kA	5800A	10kA +/-1kA
N/A	HS0-26C32RH/SAMPLE								
5962F9568903V9A	HS0-26C32EH-Q								
5962F9666302V9A	HS0-26CLV31RH-Q	Datasheet=96.5 x 195 x <b>21</b> mils SMD=96.5 x 195 x <b>21</b> mils	96.5 x 195 x <b>19 mils</b> +/-1mil	No Change	No Change	No Change	No Change	No Change	No Change
5962F9666304V9A	HS0-26CLV31EH-Q								
N/A	HS0-26CLV31RH/SAMPLE								
5962F9568902V9A	HS0-26CLV32RH-Q	Datasheet=78 x 123 x <b>21</b> mils SMD=78 x 123 x <b>21</b> mils	78 x 123 x <b>19 mils</b> +/-1mil	No Change	No Change	No Change	No Change	No Change	No Change
N/A	HS0-26CLV32RH/SAMPLE								
5962F9568904V9A	HS0-26CLV32EH-Q								
5962F9563101V9A	HS0-26CT32RH-Q	Datasheet=78 x 123 x <b>21</b> mils SMD=78 x 123 x <b>21</b> mils	78 x 123 x <b>19mils</b> +/-1mil	PSG 10kA +/-1kA	PSG 8kA +/-1kA	5800A	5800A +/-1kA	No Change	No Change
N/A	HS0-26CT32RH/SAMPLE								
5962F9563102V9A	HS0-26CT32EH-Q								
5962F9563201V9A	HS0-26CT31RH-Q	Datasheet=96.5 x 195 x <b>21</b> mils SMD=78 x 123 x <b>21</b> mils	96.5 x 195 x <b>19 mils</b> +/-1mil	PSG 10kA +/-1kA	PSG 8kA +/-1kA	5800A	5800A +/-1kA	No Change	No Change
N/A	HS0-26CT31RH/SAMPLE								
5962F9666301V9A	HS0-26C31RH-Q								
5962F9666303V9A	HS0-26C31EH-Q								